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				Application Number	10/689,855-Conf. #4217	
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STATEMENT BY APPLICANT			APPLICANT	First Named Inventor	Masanobu Shigeta	
				Art Unit	N/A	
	(Use as many she ets as necessary)			Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attorney Docket Number	21994-00064-US	

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite	Document Number	Publication Date MM-OD-YYYY	Name of Patentee or	Pages, Columns, Lines, Where
	No.1	Number-Kind Code ² (if known)		Applicant of Cited Document	Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁸ (# known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T°
200	BA	JP-04-223433	08-13-1992	Matsushita Electric Ind. Co., Ltd.		

"EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. "Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.ngv or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁸ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²		
2000	CA	Ji et al., "33.3: FRINGE-FIELD EFFECTS IN REFLECTIVE CMOS LCD DESIGN OPTIMIZATION," SID 99 DIGEST, PP. 750-753, 1999.			
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Signature	Mike Q	Considered	4-12-05
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